	Туре	L	#	Hits	Search Text	DBs	Time Stamp	Commen
1	BRS	L1	•	14	hoff near		2004/11/ 29 11:05	
2	BRS	L2		1105		US- PGPU B; USPA	2004/11/ 29 11:06	
3	BRS	L3		12	2 and ((sic) near substrate)	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:07	

	Туре	L	#	Hits	Search Text	DBs	Time Stamp	Commen
4	BRS	L4		2764	((sic) near substrate)	IH	2004/11/ 29 11:07	
5	BRS	L5		7906 6	(((sic) near substrate) or (silicon near carbide) or (silicon-carbide))	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:08	
6	BRS	L6		1/906	(((sic) near substrate)) or ((silicon near carbide) or	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:09	

		Туре	L	#	Hits	Search Text	DBs	Time Stamp	Commen
7		BRS	L7		2765	<pre>(((sic) near substrate)) or ((silicon near carbide) or (silicon-carbide)) near25 ((electric near filed))</pre>	IH: P() •	2004/11/ 29 11:09	
8	•	BRS	L8		2939	(((sic) near substrate)) or ((silicon near carbide) or (silicon-carbide)) near25 ((electric	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/29 11:09	
9		BRS	L9		2765	<pre>(((sic) near substrate)) or ((silicon near carbide) or (silicon-carbide)) near25 ((frequency near3 electric near</pre>	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:10	

	Туре	L#	Hits	Search Text	DBs	Time Stamp	Commen
10	BRS	L10	2765	(((sic) near substrate)) or ((silicon near	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:10	
11	BRS	L11	2765	carbide) or (silicon-carbide)) near25 ((frequency	IH, P() •	2004/11/ 29 11:10	
12	BRS	L12			US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:10	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Commen
13	BRS	L13	2764	<pre>(((sic) near substrate)) or ((silicon near carbide) or (silicon-carbide)) near25 ((frequency near electric near field)) near15 (excited near gas)</pre>	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:11	
14	BRS	L14	2764	<pre>(((sic) near substrate)) or ((silicon near carbide) or (silicon-carbide)) near25 ((frequency near electric near field)) near15 ((excited near gas)</pre>	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:11	
15	BRS	L15	2764	<pre>((silicon near carbide) or (silicon-carbide)) near25 ((frequency near electric near field)) near15 ((excited near gas)</pre>	EPO; JPO;	2004/11/29 11:12	

	Туре	L #	Hits	Search Text	DBs	Time Stamp	Commen
16	BRS	L16	2764	((silicon near carbide) or (silicon-carbide)) near25 ((frequency near electric near field)) near15	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:12	
17	BRS	L17	2764	near25 ((frequency near electric near field)) near15	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/29 11:13	

	Туре	L #	Hits	Search Text	DBs	Time Stamp	Commen
18	BRS	L18	0	<pre>(((frequency near electric near field)) near15 ((excited near gas) near15 (energy)) near25 (silicon near oxide near film) near15 (afterglow))</pre>	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:13	
19	BRS	L19	0	((frequency near	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:13	
20	BRS	L20	0	((electric near field) near15 (gas) near15 (energy) near25 (silicon near oxide near film) near15 (afterglow))	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:14	

	Туре	L	#	Hits	Search Text	DBs	Time Stamp	Commen
21	BRS	L2	21	0	(electric near field) near15 (gas) near15 (energy) near25 (silicon near oxide near film)	IH. 🛩 🔝 🔻	2004/11/ 29 11:14	
22	BRS	L2	22	24	(electric near field) near15 (gas)	FDO.	2004/11/ 29 11:14	
23	BRS	L2	23	0	(electric near field) near15 (gas) near25 (silicon near oxide near film) near15 (sic)	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:15	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Commen
24	BRS	L24		(electric near field) near15 (gas) near25 (silicon near oxide near film) near15 (carbide)	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:15	
25	BRS	L25		(electric near field) near15 (gas)	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:15	
26	BRS	L26	29	(electric near field) near15 (gas) near15 (silicon near carbide)	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:19	

	Туре	L	#	Hits	Search Text	DBs	Time Stamp	Commen
27	BRS	L2	7		(electric near field) near15 (gas) near15 (silicon- carbide)	IH. P. 1 *	2004/11/ 29 11:19	
28	BRS	L2	8		(electric near field) near15 (gas) near15 (sic)	US- PGPU B; USPA T;	2004/11/ 29 11:20	
29	BRS	L2	9	U	(electric near	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:20	

	Туре	L #	Hits	Search Text	DBs	Time Stamp	Commen
30	BRS	L30	0	(electric near field) near15 (oxidiz\$3 near gas) near15 (sic)	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:21	•
31	BRS	L32	0	(oxidiz\$3 near gas) near15 (sic) same	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:21	
32	BRS	L31	23	(oxidiz\$3 near gas) near15 (sic)	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 11:24	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Commen
33	BRS	L33	3672	(gas) near15 (sic)	1H P() *	2004/11/ 29 11:24	
34	BRS	L34	362	` ` ` ` <i>` `</i>	IH: P() •	2004/11/ 29 12:33	
35	BRS	L35	1123	(electric near field) near15 (energy)	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 12:21	

	Туре	L #	Hits	Search Text	DBs	Time Stamp	Commen
36	BRS	L36	214	(frequency near electric near field) near15 (energy)	IH: P() •	2004/11/ 29 12:22	
37	BRS	L37	17	(frequency near electric near field) near15 (energy) near15 (substrate or wafer)	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2004/11/ 29 12:24	
38	BRS	L38	826	field) near15	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2004/11/ 29 12;25	

	Type	L	#	Hits	Search Text	DBs	Time Stamp	Commen
39	BRS	L3	9	79	(electric near field) near15 (energy) near15 (gas) near15 (substrate or wafer)	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 12:25	
40	BRS	L4	0		((gas)) near15 ((sic or silicon	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 12:40	
41	BRS	L4	1	0	((gas)) near15 ((sic or silicon near carbide) near (wafer or substrate)) near15 (tube) near15	US- PGPU B; USPA T; EPO; DERW ENT; IBM_ TDB	2004/11/ 29 12:40	

	U	1	PT	P	Document	Issue Date	Page s	Title
1					US 2003000806 9 A1	20030109	11	Dual frequency plasma enhanced chemical vapor deposition of silicon carbide layers
2					US 2002013530 8 A1	20020926	119	Plasma process and apparatus
3					US 6589888 B2	20030708	11	Dual frequency plasma enhanced chemical vapor deposition of silicon carbide layers
4					US 6465366 B1	20021015	12	Dual frequency plasma enhanced chemical vapor deposition of silicon carbide layers
5					JP 58185418 A	19831029	≺	DEPOSITION OF THICK CARBON FILM

	U	1	PT	P	Document	Issue Date	Page s	Title
6	X				JP 03124059 A	19910527	22	Semiconductor memory with cell having cylindrical type capacitors - having fins on outer periphery of central electrode increasing surface area of signal storage electrode
7	X				JP 03124032 A	19910527	14	Formation of silicon carbide - includes depositing accelerated carbon(contg.) ions into silicon(III) crystal irradiated with ionic or atomic hydrogen and heat treating